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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

New York, New York

LAGUARTA BERTRAN, Ferran et al

Date: August 20, 2007

Serial No.:

10/568,636

Group Art Unit: 2877

Date Filed:

February 16, 2006

OPTICAL METROLOGY METHOD FOR DETERMINING THE

THREE-DIMENSIONAL TOPOGRAPHY OF AN ORIFICE AND APPARATUS

FOR DETERMINING THREE-DIMENSIONAL TOPOGRAPHIES ACCORDING

TO SAID METHOD

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

## STATUS INQUIRY LETTER

Sir:

We filed the above application with the U. S. Patent and Trademark Office on February 16, 2006.

As of this date, we have not received a first Office Action from the Patent Office. Kindly advise us of the status of this application.

Respectfully Submitted,

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